

Test report No. Page Issued date FCC ID

: 13584430H-B-R1 : 1 of 17 : December 25, 202

te : December 25, 2020 : WAZSKE45A03

EMI TEST REPORT

Test Report No.: 13584430H-B-R1

Applicant : Mitsubishi Electric Corporation Himeji works

Type of EUT : Smart Keyless System (Smart Unit)

Model Number of EUT : SKE45A-03

FCC ID : WAZSKE45A03

Test regulation : FCC Part 15 Subpart B: 2020

Test Result : Complied (Refer to SECTION 3.2)

- 1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
- 2. The results in this report apply only to the sample tested.
- 3. This sample tested is in compliance with the limits of the above regulation.
- 4. The test results in this test report are traceable to the national or international standards.
- 5. This test report must not be used by the customer to claim product certification, approval, or endorsement by the A2LA accreditation body.
- 6. This test report covers EMC technical requirements. It does not cover administrative issues such as Manual or non-EMC test related Requirements. (if applicable)
- 7. The all test items in this test report are conducted by UL Japan, Inc. Ise EMC Lab.
- 8. The opinions and the interpretations to the result of the description in this report are outside scopes where UL Japan has been accredited.
- 9. The information provided from the customer for this report is identified in SECTION 1.
- 10. This report is a revised version of 13584430H-B. 13584430H-B is replaced with this report.

Representative test engineer:

Akihiko Maeda
Engineer
Consumer Technology Division

Approved by:

Motoya Imura
Leader

Consumer Technology Division





CERTIFICATE 5107.02

	The testing in which "Non-accreditation" is displayed is outside the accreditation scopes in UL Japan.
\boxtimes	There is no testing item of "Non-accreditation".

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REVISION HISTORY

Original Test Report No.: 13584430H-B

Revision	Test report No.	Date	Page	Contents
			revised	
-	13584430H-B	December 22, 2020	-	-
(Original)				
1	13584430H-B-R1	December 25, 2020	P.5	Addition of the Voltage Controlled Oscillator
				in RF Part of Clause 2.2.
1	13584430H-B-R1	December 25, 2020	P.6	Correction of the Symbols of Result in
				Procedure of Clause 3.2;
				From "Complied#" to "Complied"
1	13584430H-B-R1	December 25, 2020	P.12	Addition of 314.720 MHz in Below 1 GHz
				data

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Reference: Abbreviations (Including words undescribed in this report)

Asymmetric Artificial Network ILAC International Laboratory Accreditation Conference ISED AC Alternating Current Innovation, Science and Economic Development Canada AM

Amplitude Modulation ISN Impedance Stabilization Network

AMN Artificial Mains Network ISO International Organization for Standardization

Amp, AMP Amplifier JAB Japan Accreditation Board ANSI American National Standards Institute LAN Local Area Network Ant, ANT Antenna LCL Longitudinal Conversion Loss

Access Point LIMS AP Laboratory Information Management System ASK Amplitude Shift Keying LISN Line Impedance Stabilization Network Atten., ATT Attenuator MRA Mutual Recognition Arrangement

Average N/A Not Applicable BPSK Binary Phase-Shift Keying NIST National Institute of Standards and Technology

BR Bluetooth Basic Rate NS No signal detect. ВТ NSA Bluetooth Normalized Site Attenuation

BT LE Bluetooth Low Energy **NVLAP** National Voluntary Laboratory Accreditation Program

BandWidth OBW Occupied Band Width BW

C.F Correction Factor OFDM Orthogonal Frequency Division Multiplexing

Cal Int Calibration Interval PK

long-term flicker severity CISPR AV CAV Ргт

CCK Complementary Code Keying POHC(A) Partial Odd Harmonic Current CDN Coupling Decoupling Network Pol., Pola. Polarization

Ch., CH PR-ASK Phase Reversal ASK Channel Comite International Special des Perturbations Radioelectriques CISPR P_{ST} short-term flicker severity

Corr. Correction QAM Quadrature Amplitude Modulation

CPE QP Customer premise equipment Quasi-Peak

CW Continuous Wave QPSK Quadri-Phase Shift Keying DBPSK Differential BPSK r.m.s., RMS Root Mean Square DC Direct Current RBW Resolution Band Width DET Detector RE Radio Equipment

REV D-factor Distance factor Reverse maximum absolute voltage change during an observation period Radio Frequency RFID Differential OPSK

DOPSK Radio Frequency Identifier DSSS RSS Direct Sequence Spread Spectrum Radio Standards Specifications EDR Enhanced Data Rate Rx

e.i.r.p., EIRP Equivalent Isotropically Radiated Power SINAD Ratio of (Signal + Noise + Distortion) to (Noise + Distortion)

EM clamp Electromagnetic clamp S/N Signal to Noise ratio EMC ElectroMagnetic Compatibility SA, S/A Spectrum Analyzer **EMI** ElectroMagnetic Interference SG Signal Generator

SVSWR EMS ElectroMagnetic Susceptibility Site-Voltage Standing Wave Ratio EN European Norm THC(A) Total Harmonic Current

e.r.p., ERP THD(%) Total Harmonic Distortion Effective Radiated Power European Union Test Receiver

EUT Equipment Under Test TxTransmitting VBW Video BandWidth Fac. Factor FCC Federal Communications Commission Vertical Vert.

Frequency Hopping Spread Spectrum xDSL. FM Generic term for all types of DSL technology Frequency Modulation

WI.AN

Wireless LAN

Frequency (DSL: Digital Subscriber Line) Freq

FSK Frequency Shift Keying Fund Fundamental

FWD Forward

GFSK Gaussian Frequency-Shift Keying **GNSS** Global Navigation Satellite System

GPS Global Positioning System

Hori. Horizontal

ICES Interference-Causing Equipment Standard

FHSS

I/O Input/Output

IEC International Electrotechnical Commission IEEE Institute of Electrical and Electronics Engineers

IF Intermediate Frequency

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SECTION 1: Customer information

Company Name : Mitsubishi Electric Corporation Himeji works Address : 840 Chiyoda-machi, Himeji, Hyogo 670-8677, Japan

Telephone Number : +81-79-298-7363 Facsimile Number : +81-79-298-9929 Contact Person : Yasuhiro Takahashi

The information provided from the customer is as follows;

- Applicant, Type of EUT, Model Number of EUT, FCC ID on the cover and other relevant pages
- Operating/Test Mode(s) (Mode(s)) on all the relevant pages
- SECTION 1: Customer information
- SECTION 2: Equipment under test (EUT) other than the Receipt Date
- SECTION 4: Operation of EUT during testing
- * The laboratory is exempted from liability of any test results affected from the above information in SECTION 2 and 4.

SECTION 2: Equipment under test (EUT)

2.1 Identification of EUT

Type : Smart Keyless System (Smart Unit)

Model Number : SKE45A-03

Serial Number : Refer to SECTION 4.2

Rating : DC 12.0 V

Receipt Date : November 11, 2020

Country of Mass-production : Japan

Condition : Production prototype

(Not for Sale: This sample is equivalent to mass-produced items.)

Modification : No Modification by the test lab

2.2 Product Description

Model: SKE45A-03 (referred to as the EUT in this report) is a Smart Keyless System (Smart Unit).

Radio Specification

LF Part *

Equipment Type : Transmitter
Frequency of operation : 125 kHz
Type of modulation : ASK
Other clock frequency : -

Antenna Type : Inductive Clock frequency (maximum) : 8 MHz

RF Part

Type of Receiver : Receiver
Frequency of operation : 315 MHz
Other clock frequency : 30.32 MHz
Intermediate frequency : 280 kHz
Antenna Type : Bar Antenna
Voltage Controlled Oscillator : 1888.32 MHz

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^{*} EUT also has this function. Please refer to No. 13584430H-A (FCC15C).

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Title

Test Specification : FCC Part 15 Subpart B

FCC Part 15 final revised on October 13, 2020 FCC 47CFR Part15 Radio Frequency Device

Subpart B Unintentional Radiators

3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result	Remarks
Conducted emission Radiated emission	FCC: ANSI C63.4: 2014 + C63.4a: 2017 7. AC power - line conducted emission measurements	FCC:Part 15 Subpart B 15.107(a)	N/A	N/A	N/A	*1)
	ISED: RSS-Gen 7.1	ISED: RSS-Gen 7.2				
	FCC: ANSI C63.4: 2014 + C63.4a: 2017 8. Radiated emission measurements ISED: RSS-Gen 7.1	FCC: Part 15 Subpart B 15.109(a)	N/A	22.9 dB 945.840 MHz, Horizontal, QP	Complied a)	-
Antenna Terminal	FCC: ANSI C63.4: 2014 + C63.4a: 2017 12. Measurement of unintentional radiators other than ITE	FCC: Part 15 Subpart B 15.111(a)	N/A	N/A	N/A	*2)
	ISED: - RSS-Gen 7.1	ISED: RSS-Gen 7.4				

^{*}Note: UL Japan, Inc's EMI Work Procedure 13-EM-W0420.

a) Refer to APPENDIX 1 (data of Radiated Emission)

Symbols:

Complied The data of this test item has enough margin, more than the measurement uncertainty.

Complied# The data of this test item meets the limits unless the measurement uncertainty is taken into consideration.

3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

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^{*1)} The test is not applicable since the EUT is not the device that is designed to be connected to the public utility (AC) power line.

^{*2)} The receiving antenna (of this EUT) is installed inside the EUT and cannot be removed (permanently attached). Therefore, Radiated emission test was performed.

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3.4 Uncertainty

There is no applicable rule of uncertainty in this applied standard. Therefore, the results are derived depending on whether or not laboratory uncertainty is applied.

The following uncertainties have been calculated to provide a confidence level of 95 % using a coverage factor k = 2.

Radiated emission

<u>Radiated emission</u>			
Measurement distance	Frequency	Uncertainty (+/-)	
3 m	30 MHz to 200 MHz	(Horizontal)	4.8 dB
		(Vertical)	5.0 dB
	200 MHz to 1000 MHz	(Horizontal)	5.2 dB
		(Vertical)	6.3 dB
10 m	30 MHz to 200 MHz	(Horizontal)	4.8 dB
		(Vertical)	4.8 dB
	200 MHz to 1000 MHz	(Horizontal)	5.0 dB
		(Vertical)	5.0 dB
3 m	1 GHz to 6 GHz		4.9 dB
	6 GHz to 18 GHz		5.2 dB
1 m	10 GHz to 26.5 GHz		5.5 dB
	26.5 GHz to 40 GHz		5.5 dB
0.5 m	26.5 GHz to 40 GHz		5.5 dB
10 m	1 GHz to 18 GHz		5.2 dB

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3.5 **Test Location**

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* AZLA Certificate Number: 5107.02/ FCC Test Firm Registration Number: 199967 / ISED Lab Company Number: 2973C

Test site	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms	M aximum measurement distance
No.1 semi-anechoic chamber	19.2 x 11.2 x 7.7	7.0 x 6.0	No.1 Power source room	10 m
No.2 semi-anechoic chamber	7.5 x 5.8 x 5.2	4.0 x 4.0	-	3 m
No.3 semi-anechoic chamber	12.0 x 8.5 x 5.9	6.8 x 5.75	No.3 Preparation room	3 m
No.3 shielded room	4.0 x 6.0 x 2.7	N/A	-	-
No.4 semi-anechoic chamber	12.0 x 8.5 x 5.9	6.8 x 5.75	No.4 Preparation room	3 m
No.4 shielded room	4.0 x 6.0 x 2.7	N/A	-	-
No.5 semi-anechoic chamber	6.0 x 6.0 x 3.9	6.0 x 6.0	-	-
No.5 measurement room	6.4 x 6.4 x 3.0	6.4 x 6.4	-	-
No.6 shielded room	4.0 x 4.5 x 2.7	4.0 x 4.5	-	-
No.6 measurement room	4.75 x 5.4 x 3.0	4.75 x 4.15	-	-
No.7 shielded room	4.7 x 7.5 x 2.7	4.7 x 7.5	-	-
No.8 measurement room	3.1 x 5.0 x 2.7	3.1 x 5.0	-	-
No.9 measurement room	8.8 x 4.6 x 2.8	2.4 x 2.4	-	-
No.11 measurement room	6.2 x 4.7 x 3.0	4.8 x 4.6	-	-

^{*} Size of vertical conducting plane (for Conducted Emission test): 2.0 m x 2.0 m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test data, Test instruments, and Test set up

Refer to APPENDIX.

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SECTION 4: Operation of EUT during testing

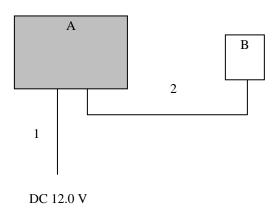
4.1 **Operating Mode(s)**

Mode	Remarks				
Receiving mode	-				
* EUT was set by the software as follows;					
Software: J979 Version 001					

^{*}The test signal level was confirmed to be sufficient to stabilize the local oscillator of the EUT.

4.2 Configuration and peripherals





^{*} Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Smart Keyless System	SKE45A-03	20201103-Е9	Mitsubishi Electric Corporation	EUT
	Smart Unit			Himeji works	
В	LED	-	-	-	-
С	Smart Keyless System	SKE45A-02	20201103-T3	Mitsubishi Electric Corporation	_
	Hand Unit			Himeji works	

List of cables used

No.	Name	Length (m)	Shi	Remarks	
			Cable	Connector	
1	DC Cable	1.7	Unshielded	Unshielded	-
2	Signal Cable	2.0	Unshielded	Unshielded	-

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^{*} It was confirmed by using LED that the EUT receives the signal from the transmitter (pair of EUT).

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SECTION 5: Radiated Emission

5.1 Operating environment

Test place : No.4 semi anechoic chamber

Temperature : See data Humidity : See data

5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane.

The EUT was set on the center of the tabletop.

Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.

Photographs of the set up are shown in Appendix 3.

5.3 Test conditions

Frequency range : 30 MHz - 200 MHz (Biconical antenna) / 200 MHz - 1000 MHz (Logperiodic antenna)

1000 MHz - 10000 MHz (Horn antenna)

Test distance : 3 m EUT position : Table top EUT operation mode : See Clause 4.1

5.4 Test procedure

The height of the measuring antenna varied between 1 and 4 m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver.

The radiated emission measurements were made with the following detector function of the Test Receiver.

For above 1 GHz, test antenna was aimed at the EUT for receiving the maximum signal and always kept within the illumination area of the 3 dB beamwidth of the antenna.

Frequency	Below 1GHz	Above 1GHz *1)
Instrument used	Test Receiver	Test Receiver
IF Bandwidth	QP: BW 120 kHz	PK: BW 1 MHz, CISPR AV: BW 1 MHz

^{*1)} The measurement data was adjusted to a 3 m distance using the following Distance Factor. Distance Factor: See Figure 2.

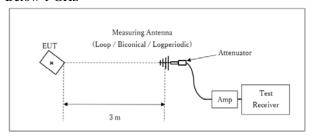
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Figure 2: Test Setup

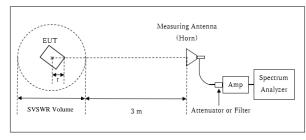
Below 1 GHz



Test Distance: 3 m

× : Center of turn table

1 GHz - 10 GHz



Distance Factor: $20 \times \log (3.9 \text{ m}/3.0 \text{ m}) = 2.28 \text{ dB}$ * Test Distance: (3 + SVSWR Volume /2) - r = 3.9 m

SVSWR Volume: 2 m

(SVSWR Volume has been calibrated based on CISPR

16-1-4.) r = 0.1 m

- r : Radius of an outer periphery of EUT
- ×: Center of turn table

- The noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

5.5 Test result

Summary of the test results: Pass

The limit is rounded down to one decimal place.

The test result is rounded off to one or two decimal places, so some differences might be observed.

Date: November 27, 2020 Test engineer: Akihiko Maeda

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APPENDIX 1: Test data

Radiated Emission

Report No. 13584430H Test place Ise EMC Lab.

Semi Anechoic Chamber No.4

Date November 27, 2020
Temperature / Humidity 23 deg. C / 43 % RH
Engineer Akihiko Maeda
(Below 1 GHz)

Mode 1

Limit: FCC_Part 15 Subpart B(15.109)_Class B

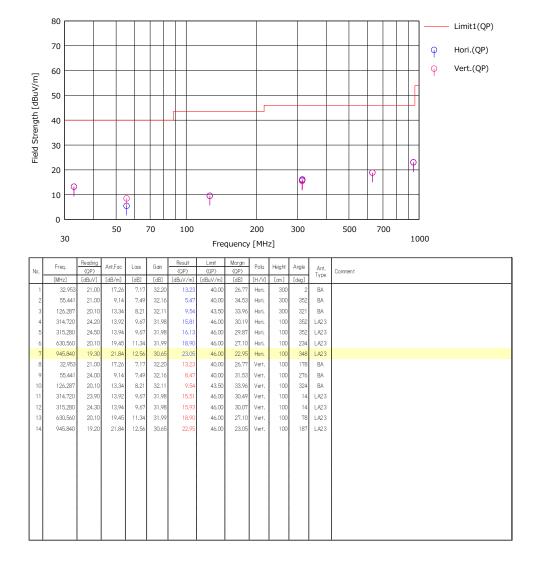


CHART: WITH FACTOR

ANT TYPE: - 30 MHz: LOOP, 30 MHz - 200 MHz: BICONICAL, 200 MHz - 1000 MHz: LOGPERIODIC, 1000 MHz -: HORN CALCULATION: RESULT = READING + ANT FACTOR + LOSS(CABLE + ATT) - GAIN(AMP)

Except for the above table: adequate margin data below the limits.

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Radiated Emission

Report No. 13584430H Test place Ise EMC Lab.

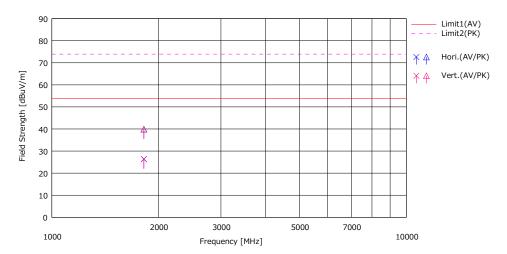
Semi Anechoic Chamber No.4

November 27, 2020 Temperature / Humidity 23 deg. C / 43 % RH Engineer Akihiko Maeda

(Above 1 GHz)

Mode 1 Mode

Limit: FCC_Part 15 Subpart B(15.109)_Class B



	_	Red	ding			0.	Res	sult	Li	nit	Ma	rgin	Б.				
No.	Freq.	(AV)	(PK)	Ant Fac	Loss	Gain	(AV)	(PK)	(AV)	(PK)	(AV)	(PK)	Pola.	Height	Angle	Ant. Type	Comment
	[MHz]	[dBuV]	[dBuV]	[dB/m]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dBuV/m]	[dBuV/m]	[dB]	[dB]	[H/V]	[cm]	[deg]	Type	
1	1818.576	29.20	42.70	25.32	4.31	32.43	26.40	39.90	53.90	73.90	27.5	34.0	Hori.	100	0	H21	
2	1818.576	29.20	42.70	25.32	4.31	32.43	26.40	39.90	53.90	73.90	27.5	34.0	Vert.	100	0	H21	

CHART: WITH FACTOR

ANT TYPE: - 30 MHz: LOOP, 30 MHz - 200 MHz: BICONICAL, 200 MHz - 1000 MHz: LOGPERIODIC, 1000 MHz -: HORN

CALCULATION: RESULT = READING + ANT FACTOR + LOSS(CABLE + D-factor) - GAIN(AMP)

Except for the above table: adequate margin data below the limits.

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^{*}The VCO (1888.32 MHz) was measured and the level was below Floor Noise.

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APPENDIX 2: Test instruments

Test equipment

Test Item		LIMS ID	Description	Manufacturer	Model	Serial	Last Calibration Date	Cal Int
RE	MAEC-04	142011	AC4_Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-10005	05/25/2020	24
RE	MOS-15	141562	Thermo-Hygrometer	CUSTOM. Inc	CTH-201	0010	01/07/2020	12
RE	MMM-10	141545	DIGITAL HITESTER	Hioki	3805	51201148	01/06/2020	12
RE	MJM-29	142230	Measure	KOMELON	KMC-36	-	-	_
RE	COTS-ME MI-02	178648	EMI measurement program	TSJ (Techno Science Japan)	TEPTO-DV	-	_	-
RE	MAEC-04- SVSWR	142017	AC4_Semi Anechoic Chamber(SVSWR)	TDK	Semi Anechoic Chamber 3m	DA-10005	04/04/2019	24
RE	MTR-10	141951	EMI Test Receiver	Rohde & Schwarz	ESR26	101408	03/10/2020	12
RE	MBA-05	141425	Biconical Antenna	Schwarzbeck Mess - Elektronik	VHA9103+BBA9106	VHA 91031302	08/31/2020	12
RE	MLA-23	141267	Logperiodic Antenna (200-1000MHz)	Schwarzbeck Mess - Elektronik	VUSLP9111B	9111B-192	09/02/2020	12
RE	MAT-34	141331	Attenuator(6dB)	TME	UFA-01	-	02/05/2020	12
RE	MCC-50	141397	Coaxial Cable	UL Japan	-	-	11/06/2020	12
RE	MPA-13	141582	r	SONOMA INSTRUMENT	310	260834	02/10/2020	12
RE	MHA-21	141508	Horn Antenna 1-18GHz	Schwarzbeck Mess - Elektronik	BBHA9120D	557	05/22/2020	12
RE	MCC-246	199563	Microwave Cable	HUBER+SUNER	SF126E/11PC35/11PC35/ 1000M,5000M	537061/126E / 537072/126E	06/11/2020	12
RE	MPA-12	141581	-	Keysight Technologies Inc	83017A	00650	10/19/2020	12

^{*}Hyphens for Last Calibration Date and Cal Int (month) are instruments that Calibration is not required (e.g. software), or instruments checked in advance before use.

The expiration date of the calibration is the end of the expired month.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

Test item:

RE: Radiated emission

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